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THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

JAMES BROC STIRTON KEVIN R. LENSING HORMUZDIAR E. NARIMAN STEVEN P. REEVES

Serial No.: 10/084,987

Filed: February 28, 2002

For: METHOD OF USING HIGH YIELD SPECTRA SCATTEROMETRY MEASUREMENTS TO CONTROL SEMICONDUCTOR MANUFACTURING

PROCESSES, AND SYSTEMS FOR

ACCOMPLISHING SAME

Examiner: Roy M. Punnoose

Group Art Unit: 2877

Att'y Docket: 2000.092400/TT5002

Customer No.: 23720

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**PATENT** 

## **RESPONSE TO OFFICE ACTION DATED SEPTEMBER 5, 2003**

CERTIFICATE OF MAILING 37 C.F.R 1.8

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date below:

Sir:

Date

October 29, 2003

This paper is submitted in response to the Office Action dated September 5, 2003, for which the three-month date for response is December 5, 2003.

No fee is believed to be due in connection with the present paper. However, the Director is authorized to deduct any fees required under 37 C.F.R. §§ 1.16 to 1.21, from Advanced Micro Devices, Inc. Deposit Account No. 01-0365/TT5002. In the event the monies in that account are insufficient, the Director is authorized to withdraw funds from Williams, Morgan & Amerson, P.C. Deposit Account No. 50-0786/2000.092400.